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Abstract

Probe for electrical measurement methods, and use of a flexible probe for production of an inflexible probe

Probes according to the prior art have a substrate which is mechanically rigid. The probe can therefore move only on planar surfaces.

A probe (1) according to the invention has a flexible substrate (16) such that it is sufficiently flexible to allow the probe (1) to be matched to different radii of curvature of a test body (10).

Figure 2